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# N-Channel 800V (D-S) Super Junction Power MOSFET

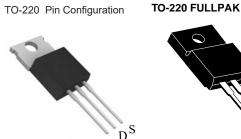
PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	800			
R <sub>DS(on)</sub> max. at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.24		
Q <sub>g</sub> max. (nC)	140			
Q <sub>gs</sub> (nC)	21			
Q <sub>gd</sub> (nC)	37			
Configuration	Single			

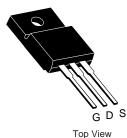
### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>a</sub>)
- Avalanche energy rated (UIS)

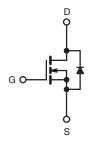
### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial









N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			$V_{DS}$	800	V		
Gate-Source Voltage			$V_{GS}$	± 30	V		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	\/ at 10 \/	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	- I <sub>D</sub>	20	А		
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		15			
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	76			
Linear Derating Factor				2.2	W/°C		
Single Pulse Avalanche Energy b			E <sub>AS</sub>	691	mJ		
Maximum Power Dissipation			$P_{D}$	250	W		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C			
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		dV/dt 37	37	V/ns		
Reverse Diode dV/dt <sup>d</sup>		uv/at	18	V/IIS			
Soldering Recommendations (Peak Temperature) c for 10 s			300	°C			

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 28.2 mH,  $R_q$  = 25  $\Omega$ ,  $I_{AS}$  = 7 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ ,  $dI/dt = 100 \text{ A/}\mu\text{s}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ .



# DTN20N80SJ/DTP20N80SJ/DTP20N80FSJ

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THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.55	G/ VV		

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static		-					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		800	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I <sub>D</sub> = 1 mA		0.74		V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$		2	-	4	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
			V <sub>GS</sub> = ± 30 V	-	-	± 1	μΑ
Zoro Coto Voltago Drain Current	1	$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	-	1	μА
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			-	-	10	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 11 A	-	0.24	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 8 V, I <sub>D</sub> = 5 A		-	9.2	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ f = 1  MHz		-	3315	-	pF
Output Capacitance	C <sub>oss</sub>			-	148	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	4	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	89	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	307	-	
Total Gate Charge	Qg			-	73	110	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 520 \text{ V}$		15	-	nC
Gate-Drain Charge	Q <sub>gd</sub>				32	-	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 11 A,		-	22	45	- ns
Rise Time	t <sub>r</sub>			-	33	66	
Turn-Off Delay Time	t <sub>d(off)</sub>	V <sub>GS</sub> =	$V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		73	110	
Fall Time	t <sub>f</sub>	1		-	38	76	
Gate Input Resistance	$R_g$	f = 1 MHz, open drain		-	0.64	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	76	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 11 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 11 A, dl/dt = 100 A/μs, V <sub>R</sub> = 400 V		-	400	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	5.9	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			_	20	_	A

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

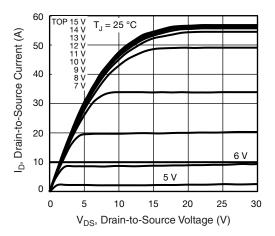


Fig. 1 - Typical Output Characteristics

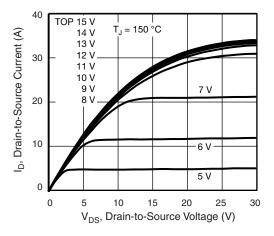


Fig. 2 - Typical Output Characteristics

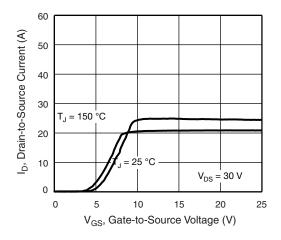


Fig. 3 - Typical Transfer Characteristics

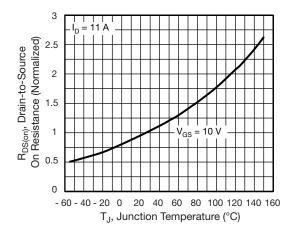


Fig. 4 - Normalized On-Resistance vs. Temperature

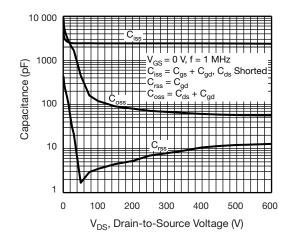


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

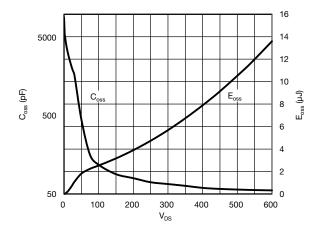


Fig. 6 -  $C_{\text{oss}}$  and  $E_{\text{oss}}$  vs.  $V_{\text{DS}}$ 



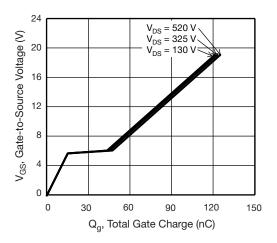


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

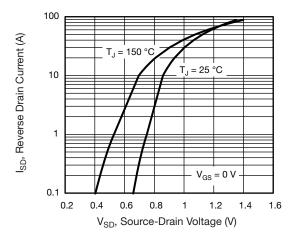


Fig. 8 - Typical Source-Drain Diode Forward Voltage

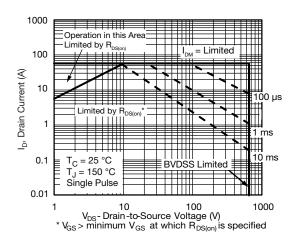


Fig. 9 - Maximum Safe Operating Area

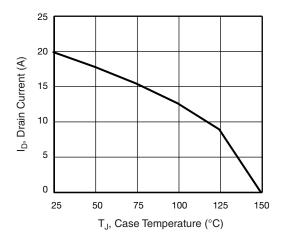


Fig. 10 - Maximum Drain Current vs. Case Temperature

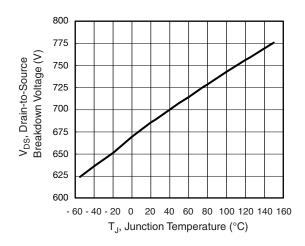


Fig. 11 - Temperature vs. Drain-to-Source Voltage



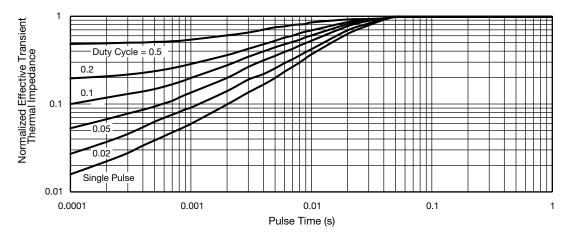


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

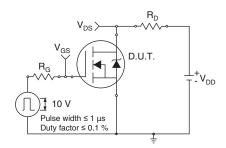


Fig. 13 - Switching Time Test Circuit

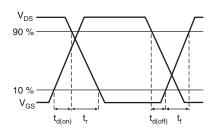


Fig. 14 - Switching Time Waveforms

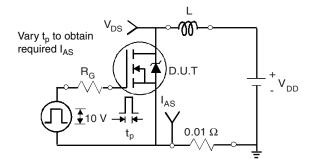


Fig. 15 - Unclamped Inductive Test Circuit

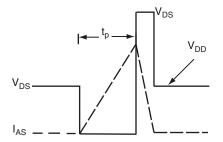


Fig. 16 - Unclamped Inductive Waveforms

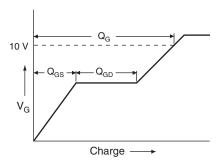


Fig. 17 - Basic Gate Charge Waveform

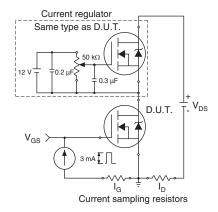
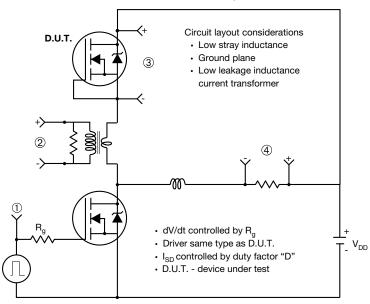


Fig. 18 - Gate Charge Test Circuit

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## Peak Diode Recovery dV/dt Test Circuit



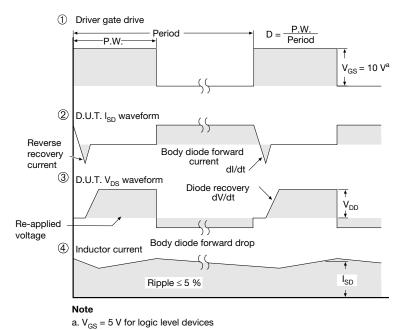


Fig. 19 - For N-Channel



SEMICONDUCTOR

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